

MT2168

Benchmark Pick & Place Handler >>

1 Base System

- 1.1 Available Versions:
- ambient, ambient hot (+ 155° C standard, +175° C optional)
 - up to 16 contact sites
- 1.2 Available Options (Selection):
- vision alignment system

2 Package Style Conversion

- 2.1 Conversion Kits:
- uses conversion kits for easy package style conversion
- 2.2 Required Conversion Time:
- less than 10 min for 1 person
- 2.3 Adjustments:
- no adjustments required after package style conversion

3 Packages

- 3.1 Conversion Kits for:
- QFP, BGA, μ BGA, PLCC, TSSOP, CSP, QFN (MLF/MLP), PGA, LGA, MCM, other package styles on request
- 3.2 Min. and Max. Size of Packages:
- 3x3 to 70x70 mm
 - min. lead pitch: down to 0.4 mm (standard set-up)
 - down to 0.3 mm (with vision alignment option)

4 Loading/ Unloading

- 4.1 Loading/Unloading Material and Size:
- all commonly used trays acc. to JEDEC standard CO-012, CO-029 and CO-034, others on request.
- 4.2 Type of Loader:
- tray stack, separate input/output tray loop
- 4.3 Loading/Unloading Possible During Operation:
- yes

5 Contacting

- 5.1 Contact Modes:
- single
 - parallel
 - ping-pong
- 5.2 Applications:
- short contact ambient (plunge to board)
 - short contact hot (plunge to board)
 - standard (including temperature insulation)
- 5.3 Available Contact Sockets:
- Multitest offers contact sockets for all package versions and applications, i.e. standard, high frequency and Kelvin.
 - Sockets from other suppliers may be used, e.g. ECT, Yamaichi, Synergetix, JTI, Enplas, Aries, OzTek, Seiken - others on request.

6 Temperature Accuracy

- 6.1 Test Site Accuracy:
- +/- 2° C
 - +/- 1° C after kit specific calibration
- 6.2 Test Site Temperature Stability:
- +/- 0.5° C

7 Bin Categories

- 7.1
- 5 tray categories (stack or manual)
 - software binning categories: 32

8 Docking

- 8.1 Docking Height:
- 966 mm (center of sockets)
- 8.2 Compatibility:
- all commonly used docking systems and test heads are supported.

9 Performance

- 9.1 Throughput:
- example x16 mode: 20,000 uph at 2.5 s test time
- 9.2 Index Time:
- (virtual index time for multiple contact sites)
- single mode: 0.380 s
 - dual mode: 0.190 s / device
 - quad mode: 0.095 s / device
 - octal mode: 0.048 s / device
 - x16 mode: 0.024 s / device

10 Compliance and Standards

- 10.1 Compliant to:
- CE

All performance specification such as MTBF, MTBA, Uptime, Yield and Jam Rate assume that only original Multitest spare and consumable parts are used, recommended maintenance intervals are respected, operators/maintenance technicians have successfully participated in a formal equipment training by Multitest, and only Multitest approved software is used on the systems. Multitest assumes no warranty or liability if any of these requirements is not met.